

Notice of References Cited	Application/Control No. 10/815,640	Applicant(s)/Patent Under Reexamination LAPSTUN ET AL.	
	Examiner Madeleine AV Nguyen	Art Unit 2626	Page 1 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,231,663 A	07-1993	Earl et al.	382/159
	B	US-5,464,971 A	11-1995	Sutcliffe et al.	235/379
	C	US-5,486,686 A	01-1996	Zdybel et al.	235/375
	D	US-5,513,013 A	04-1996	Kuo, Youti	358/448
	E	US-5,514,860 A	05-1996	Berson, William	235/468
	F	US-6,469,089	10-2002	Wang et al.	524/492
	G	US-5,684,069 A	11-1997	Auslander, Judith D.	524/88
	H	US-5,825,947 A	10-1998	Sasaki et al.	382/321
	I	US-6,603,864	08-2003	Matsunoshita, Junichi	382/100
	J	US-6,476,834 B1	11-2002	Doval et al.	715/863
	K	US-2002/0194417 A1	12-2002	Suzuki et al.	710/305
	L	US-6,789,040 B2	09-2004	Kaushikkar, Shantanu V.	702/150
	M	US-6,820,807 B1	11-2004	Antognini et al.	235/454

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

C

Notice of References Cited	Application/Control No. 10/815,640	Applicant(s)/Patent Under Reexamination LAPSTUN ET AL.	
	Examiner Madeleine AV Nguyen	Art Unit 2626	Page 2 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,158,747 A	06-1979	Muller et al.	178/19.03
	B	US-5,438,430 A	08-1995	Mackinlay et al.	358/450
	C	US-5,544,265 A	08-1996	Bozinovic et al.	382/203
	D	US-5,572,674 A	11-1996	Ernst, Theodore R.	709/221
	E	US-5,630,168 A	05-1997	Rosebrugh et al.	710/5
	F	US-5,751,470 A	05-1998	Damon, Brian Wesley	358/3.23
	G	US-4,739,377	04-1988	Allen, James D.	355/133
	H	US-6,005,973 A	12-1999	Seybold et al.	382/187
	I	US-6,021,217 A	02-2000	Nakahara, Nobuhiko	382/169
	J	US-6,100,996 A	08-2000	Amano et al.	358/1.9
	K	US-6,456,740 B1	09-2002	Carini et al.	382/187
	L	US-6,789,040 A1	09-2004	Kaushikkar, Shantanu V.	702/150
	M	US-6,587,126 B1	07-2003	Wakai et al.	715/744

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/815,640	Applicant(s)/Patent Under Reexamination LAPSTUN ET AL.	
	Examiner Madeleine AV Nguyen	Art Unit 2626	Page 3 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,501,931 A	02-1985	Ohya et al.	345/175
	B	US-4,532,596 A	07-1985	Pugsley, Peter C.	700/125
	C	US-5,235,654 A	08-1993	Anderson et al.	382/180
	D	US-5,742,705 A	04-1998	Parthasarathy, Kannan	382/185
	E	US-5,777,605 A	07-1998	Yoshinobu et al.	345/173
	F	US-5,822,546 A	10-1998	George, Stanley W.	710/303
	G	US-5,848,426 A	12-1998	Wang et al.	715/505
	H	US-5,945,972 A	08-1999	Okumura et al.	345/98
	I	US-5,995,193 A	11-1999	Stephany et al.	355/31
	J	US-6,035,308 A	03-2000	Yano et al.	715/501.1
	K	US-6,129,278 A	10-2000	Wang et al.	235/462.01
	L	US-6,490,681 B1	12-2002	Kobayashi et al.	713/171
	M	US-6,587,126 B2	07-2003	Wakai et al.	715/744

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

C

Notice of References Cited	Application/Control No. 10/815,640	Applicant(s)/Patent Under Reexamination LAPSTUN ET AL.	
	Examiner Madeleine AV Nguyen	Art Unit 2626	Page 4 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,270,146 A	05-1981	Adachi, Eiichi	358/450
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.